

## General Description

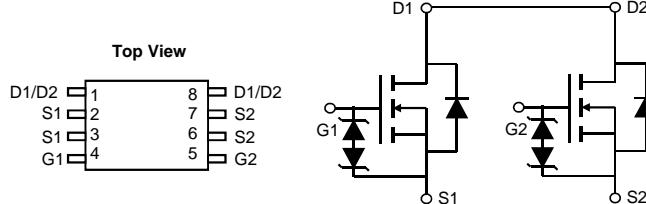
The AO8820 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V while retaining a 12V  $V_{GS(MAX)}$  rating. It is ESD protected. This device is suitable for use as a uni-directional or bi-directional load switch, facilitated by its common-drain configuration.

## Features

$V_{DS}$	20V
$I_D$ (at $V_{GS}=10V$ )	7A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 21mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 24mΩ
$R_{DS(ON)}$ (at $V_{GS}=3.6V$ )	< 28mΩ
$R_{DS(ON)}$ (at $V_{GS}=2.5V$ )	< 32mΩ
$R_{DS(ON)}$ (at $V_{GS}=1.8V$ )	< 50mΩ



**ESD protected!**



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current	$I_D$	7	A
$T_A=70^\circ\text{C}$	$I_D$	5.5	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	30	
Power Dissipation <sup>B</sup>	$P_D$	1.5	W
$T_A=70^\circ\text{C}$	$P_D$	0.96	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	64	83	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>		89	120	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	53	70	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$			10	$\mu\text{A}$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.5	0.8	1.1	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	30			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=7\text{A}$ $T_J=125^\circ\text{C}$	13	17.2	21	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=6.6\text{A}$	15	19.4	24	
		$V_{GS}=3.6\text{V}, I_D=6\text{A}$	16	20.7	28	
		$V_{GS}=2.5\text{V}, I_D=5.5\text{A}$	18	25	32	
		$V_{GS}=1.8\text{V}, I_D=2\text{A}$		35	50	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=7\text{A}$		25		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.65	1	V
$I_S$	Maximum Body-Diode Continuous Current				2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		500		pF
$C_{\text{oss}}$	Output Capacitance			100		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			52		pF
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=7\text{A}$		6	9	nC
$Q_{\text{gs}}$	Gate Source Charge			2		nC
$Q_{\text{gd}}$	Gate Drain Charge			1		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=5\text{V}, V_{DS}=10\text{V}, R_L=1.4\Omega, R_{\text{GEN}}=3\Omega$		0.2		us
$t_r$	Turn-On Rise Time			1.5		us
$t_{\text{D(off)}}$	Turn-Off Delay Time			7.4		us
$t_f$	Turn-Off Fall Time			18		us
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=7\text{A}, dI/dt=100\text{A}/\mu\text{s}$		9		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=7\text{A}, dI/dt=100\text{A}/\mu\text{s}$		10		nC

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QJL}}$  and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

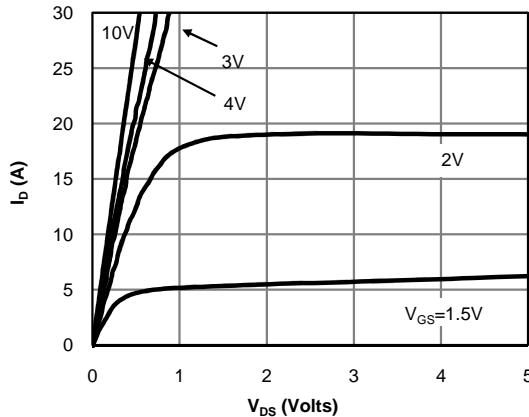
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Fig 1: On-Region Characteristics (Note E)

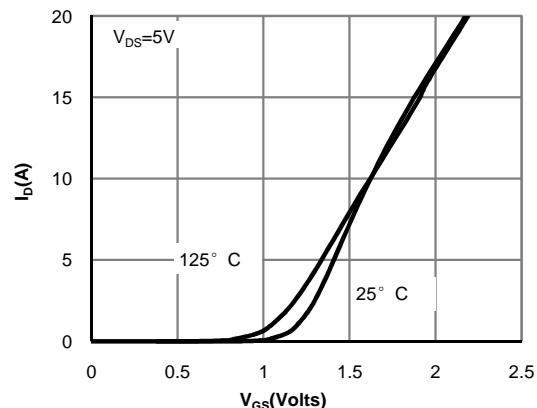


Figure 2: Transfer Characteristics (Note E)

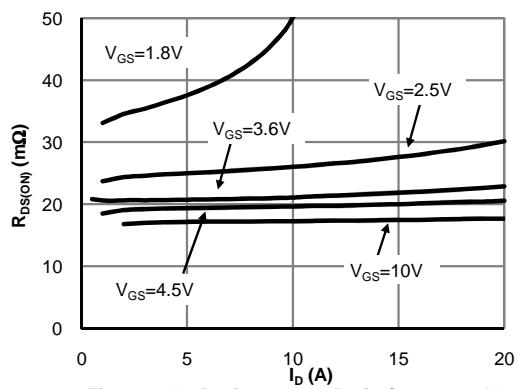


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

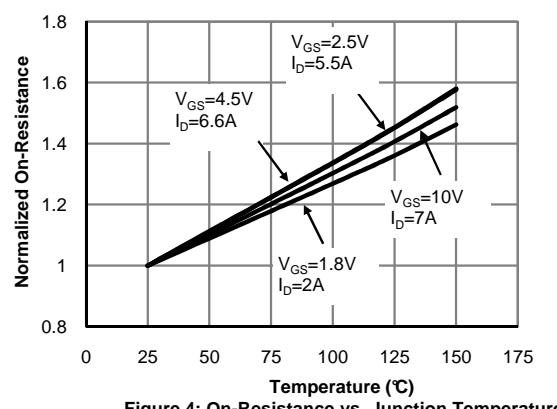


Figure 4: On-Resistance vs. Junction Temperature (Note E)

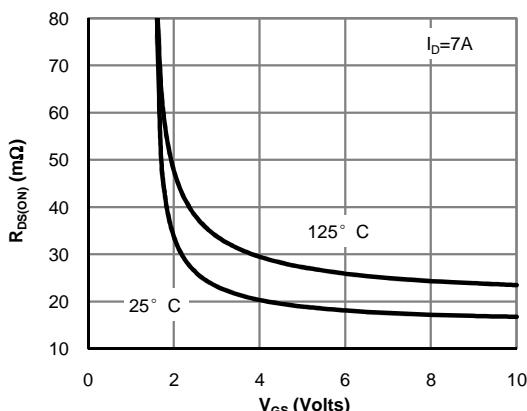


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

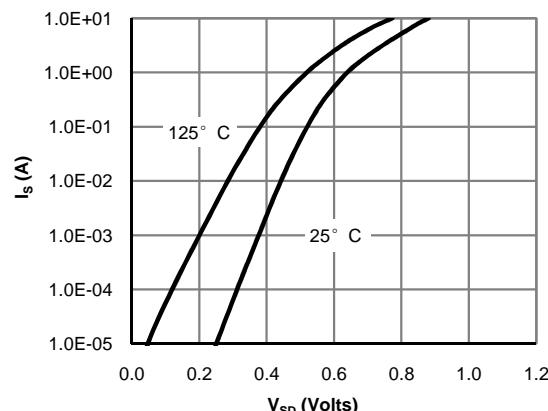


Figure 6: Body-Diode Characteristics (Note E)

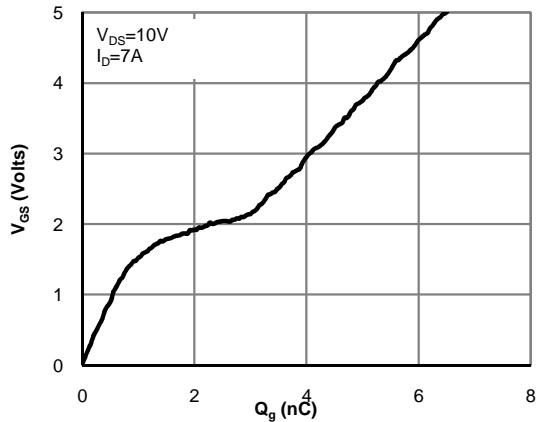
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 7: Gate-Charge Characteristics

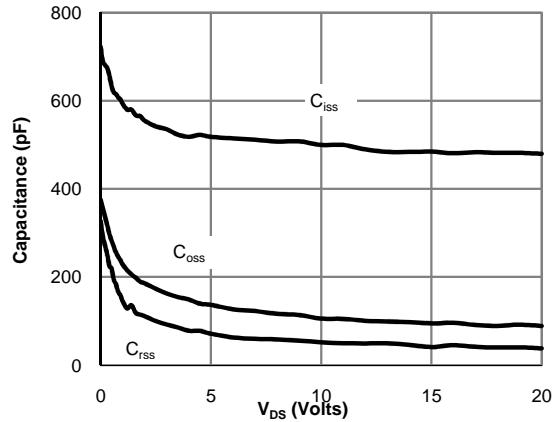


Figure 8: Capacitance Characteristics

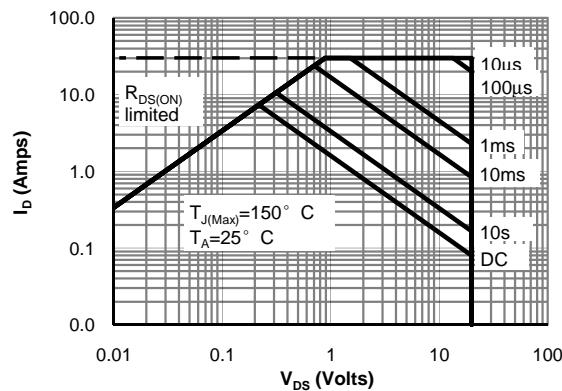


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

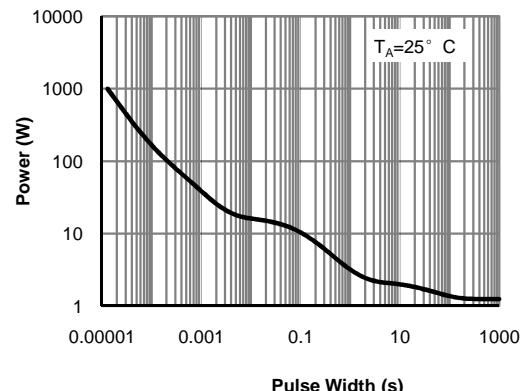


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

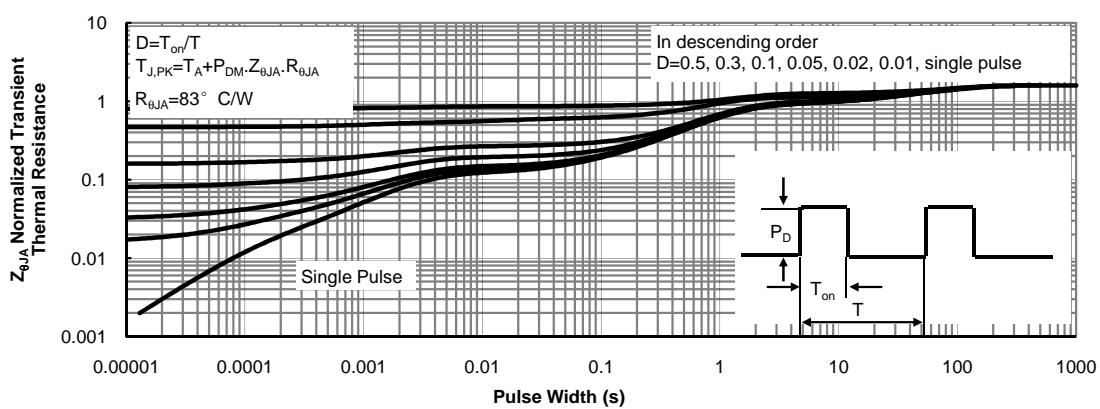
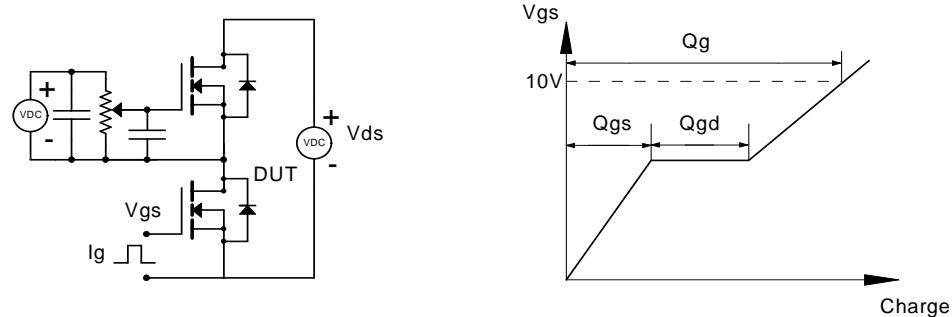
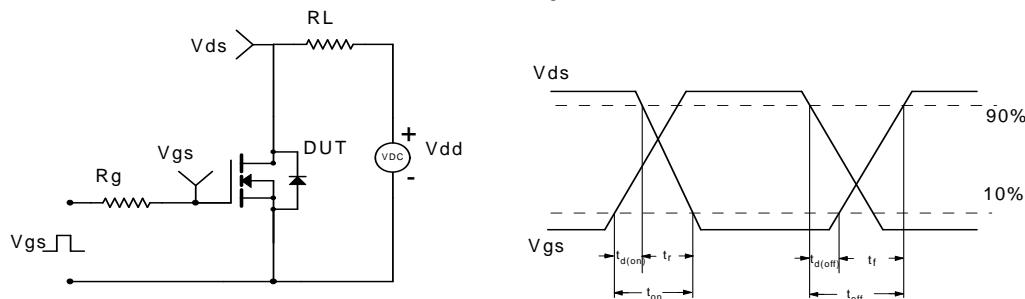


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit &amp; Waveform



Resistive Switching Test Circuit &amp; Waveforms



Diode Recovery Test Circuit &amp; Waveforms

